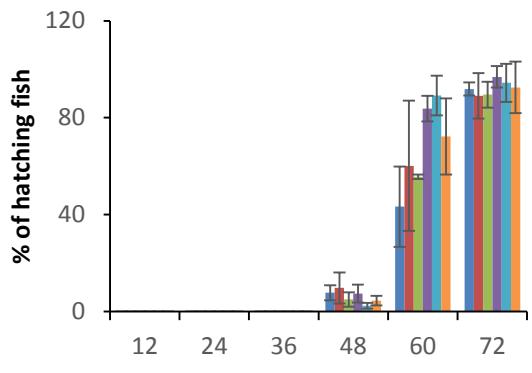
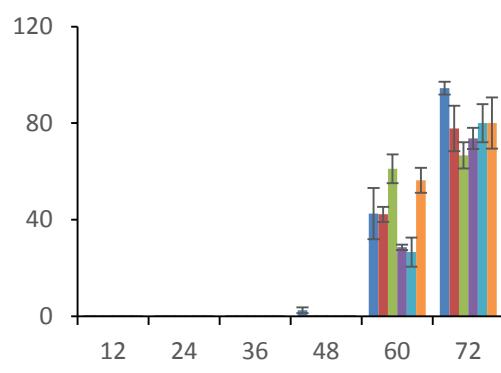


Figure S1. Survival rate at each time point of 12, 24, 36, 48, 60, and 72 hpf after exposure to 3.125, 6.25, 12.5, 25, 50, and 100 mg/L of 25- or 115-nm SiO₂ NPs with different surface charges. Data are represented as mean \pm SD (standard deviation).

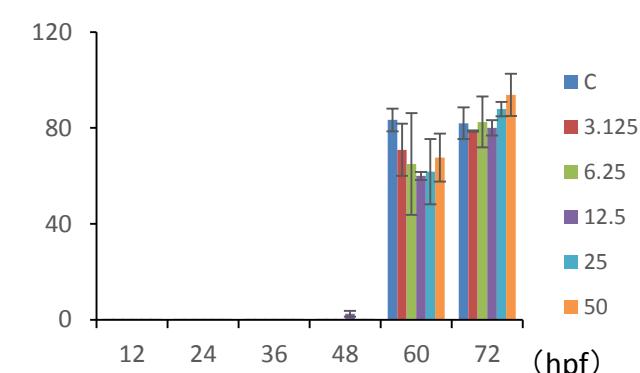
+q, 25 nm SiO₂ NPs



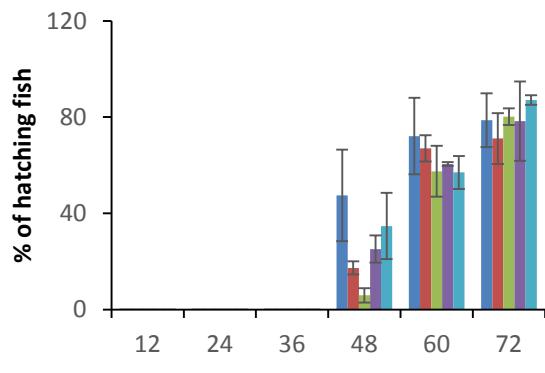
N, 25 nm SiO₂ NPs



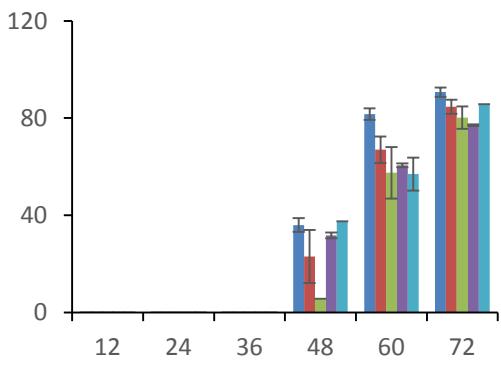
N, 115 nm SiO₂ NPs



+q, 115 nm SiO₂ NPs



-q, 115 nm SiO₂ NPs



-q, 25 nm SiO₂ NPs

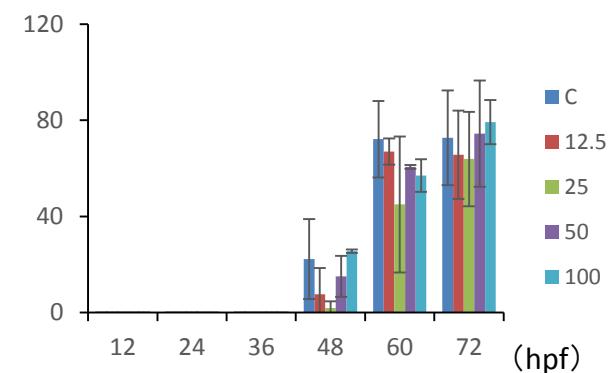


Figure S2. Hatching rate at each time point of 12, 24, 36, 48, 60, and 72 hpf after exposure to 3.125, 6.25, 12.5, 25, 50, and 100 mg/L of 25- or 115-nm SiO₂ NPs with different surface charges. Data are represented as mean \pm SD (standard deviation).